



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **YAMAGISHI, Yasuo, et al.**

Group Art Unit: **2829**

Serial No.: **10/621,445**

Examiner: **Jermele M. HOLLINGTON**

Filed: **July 18, 2003**

P.T.O. Confirmation No.: **1112**

For: **PROBE CARD AND TESTING METHOD OF SEMICONDUCTOR CHIP,  
CAPACITOR AND MANUFACTURING METHOD THEREOF**

**PRELIMINARY AMENDMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

October 19, 2005

Sir:

This Preliminary Amendment is being filed concurrently with a Request for Continued Examination in response to the Final Office Action dated **June 27, 2005**, extended to **October 27, 2005** by a **one (1)** month Petition for Extension of Time. Prior to further examination, please amend the above-identified application as follows: